

2014 CAP Congress / Congrès de l'ACP 2014

Thursday, 19 June 2014

(R1-3) Ion Beam Analysis and Modification - DCMMP / Analyse et modification de faisceaux d'ions - DPMCM - C-304

(08:45 - 10:30)

-Conveners: François Schiettekatte

time	[id] title	presenter
08:45	[278] High Resolution Depth Profiling for Studying Titanium Oxidation	Mr BROCKLEBANK, Mitchell
09:00	[344] Characterization of PICASSO/PICO detectors using University of Montreal Tandem Van de Graaff accelerator	LAURIN, Mathieu
09:15	[324] Measurement of hyperuniformity in pure amorphous silicon	ROORDA, Sjoerd
09:30	[332] Defect complex evolution in semiconductors: long-range elastic interactions matter	SCHIETTEKATTE, François
09:45	[274] Medium energy ions for thin films and monolayers	GONCHAROVA, Lyudmila
10:00	[382] Toward pump-probe experiments of defect dynamics with pulsed ion beams	SEIDL, Peter